Issue	Classification

Application/Control No

10/792,218 Examiner

Amy R. Cohen

Applicant(s)/Patent	unde
Reexamination	

SATOH ET AL.

Art Unit

	ISSUE CLASSIFICATION											
	ORIGINAL					CROSS REFERENCE(S)						
(CLASS SUBCLASS				CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)						
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Amy R. Cohen 2
(Agsistant Examiner)

2/8/2006 (Date)

(Legal Instruments Examiner) (Date)

Diego Gutierrez
Supervisory Patent Examiner

Technology Center 2800
(Primary Examiner) (Date

Total Claims Allowed: 22

O.G. O.G. Print Claim(s) Print Fig.

Claims renumbered in the same order as presented by applicant ☐ CPA ☐ T.D. ☐ R.1.47 Original Original Original Original Original Original Original Final Final Final Final Final